Frontiers of Materials Science

Electronic Supplementary Material

Investigation on characteristics of the graphene film on various crystal planes of polycrystalline aluminum nitride

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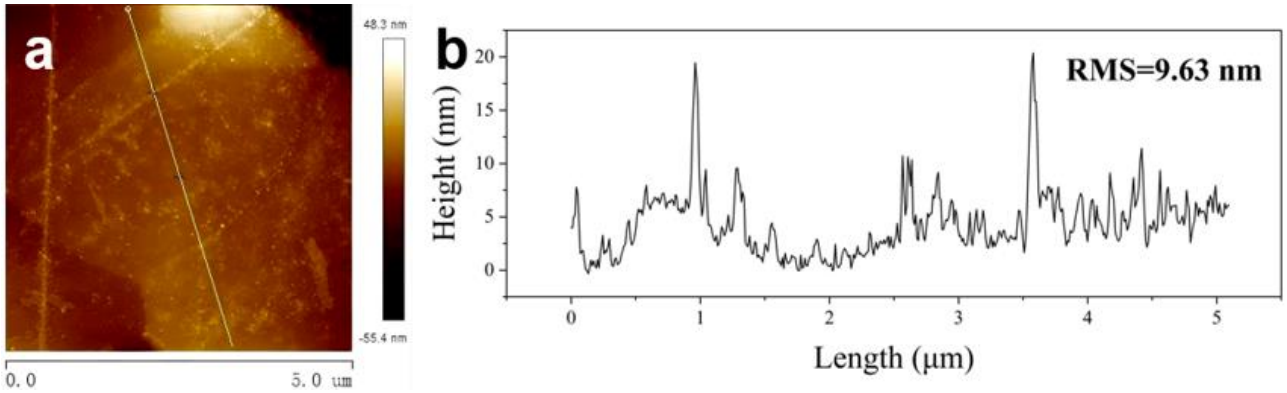

Fig. S1 (a) Height topography of an AFM image. **(b)** Height profile along the white path in Panel (a).

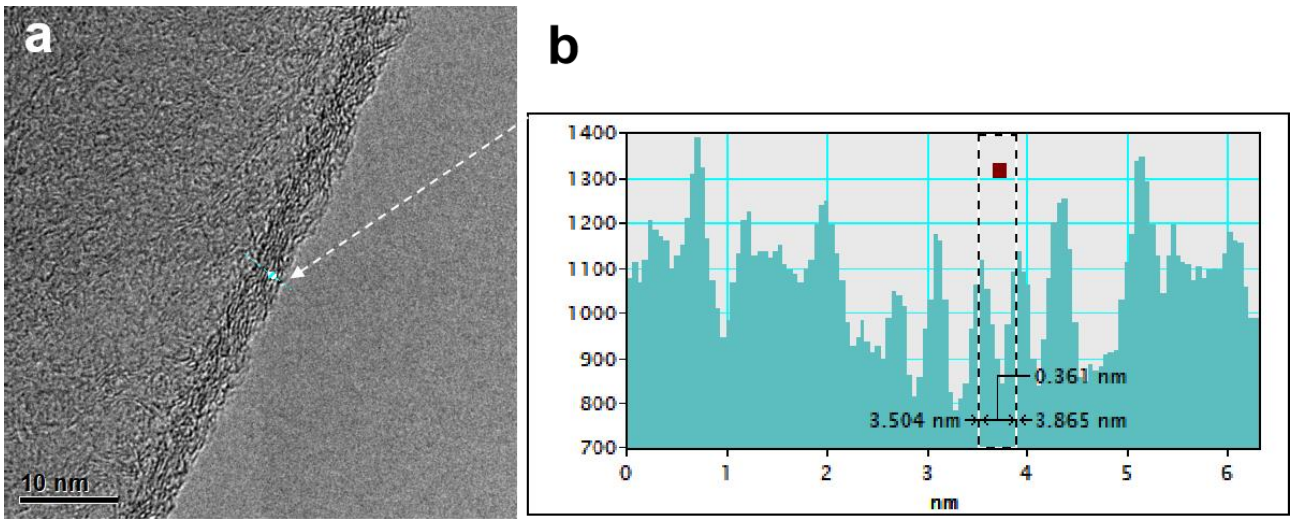

Fig. S2 (a) HR-TEM image of the graphene film prepared by SEMI quenching on the surface of polycrystalline AlN. **(b)** In the corresponding area, the spacing of the crystal surface is analyzed, and the spacing of the crystal surface is 0.361 nm.